

<b>Notice of References Cited</b>	Application/Control No. 10/710,855	Applicant(s)/Patent Under Reexamination CHANG, SUNG-SAN	
	Examiner Henok G. Heyi	Art Unit 2627	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,123,005 A	06-1992	Kurosu, Tadao	720/602
*	B	US-6,005,833 A	12-1999	Yasuma et al.	720/602
*	C	US-6,370,100 B2	04-2002	Koshino et al.	720/602
*	D	US-2005/0204373 A1	09-2005	Ueno et al.	720/616
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.